

SYMBOL

30V, 8A (1) N-Channel MOSFET

- Advanced Trench Device Design and Processes
- High Reliability Capability
- Sampled CP Probing and Inking

Gate of Source

Electrical Characteristics in C/P Test (T _J at 25 $^\circ C$)						
Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Condition
V _{(BR)DSS}	Drain-Source Breakdown Voltage	30			V	V _{GS} =0V, I _D =250µA
R _{DS(ON)}	Static Drain-Source On-Resistance		17.4	22.5	mΩ	$V_{GS} = 10V, I_{D} = 1A(2)$
V _{GS (th)}	Gate Threshold Voltage	1		2.5	V	V_{DS} = V_{GS} , I_D =250 μ A
I _{DSS}	Drain-to-Source Leakage Current			1	μA	V _{DS} =30V, V _{GS} =0V
I _{GSS}	Gate-to-Source Leakage Current	-100	_	100	nA	V _{DS} =0V, V _{GS} =±20V
T _J , T _{STG}	Operating and Storage Temperature	-55℃ to 150℃ Max.				

Mechanical Data Die Drawing Chip Size 450 µm X 1311 µm 450um Gate Pad Size 174 µm X 170 µm Source Pad Size 365 µm X 1227 µm 365.6um Scribe Line Width 60 µm Wafer Thickness 125 µm Wafer Diameter 200 mm 310.9um Gross Die 41305 EA Source Metallization Al-Cu (4µm typical) **Drain Metallization** Ti-Ni-Ag Passivation N/A Store in original container, in dry nitrogen, 6 **Recommended Storage** months at ambient temperature of 23°C ± 3°C Environment

(1) This characteristic assumes the die is assembled in SOP-8 package. Actual performance may degrade when assembled.

(2) Pulse Width tp = < 1 mS, Duty Cycle < 2%.



Specific Assembly Info	Die Drawing	
Package Type	SOP-8	450um
Die Attach Method	Soft solder	365.6um
Soft Solder Composition	Pb,Sn,Ag	
Gate Wire Bonding	Cu, 2 mil x1	1310.9ur 1226.5um
Source Wire Bonding	Cu, 2 mil x8	
Molding Compound Manufacturer	G700HF	
Solder Plating Composition	Pure Tin	

Position			Bonding Diagram Top View	
	X (um)	Y (um)	ZERO	
ZERO	0	0	1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1	
ТОР	1310.9	450		
S1	52.2	52.2		
S2	1107.05	397.8		
S3	1258.7	242.85		
G1	1133.05	268.85	<u>ه</u>	
G2	1283.7	422.8	aot log	



Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Condition
I _{DSS}	Drain-to-Source Leakage Current	_	_	1	μA	V _{DS} =30V, V _{GS} =0V
I _{GSSF}	Gate-to-Source Leakage Current			100	nA	V _{DS} =0V, V _{GS} =+20V
I _{GSSR}	Gate-to-Source Leakage Current	-100	_		nA	V _{DS} =0V, V _{GS} =-20V
BV _{DSS}	Drain-Source Breakdown Voltage	30	_		V	V _{GS} =0V, I _D =250µA
BV _{DSS}	Drain-Source Breakdown Voltage	30	_		V	V _{GS} =0V, I _D =1mA
R _{DS(ON)}	Static Drain-Source On-Resistance	_		26	mΩ	V _{GS} =10V, I _D =8A
$V_{GS(th)}$	Gate Threshold Voltage	1		2.5	V	V_{DS} = V_{GS} , I_D =250 μ A
V _{SD}	Drain-Source Diode Forward Voltage			1.1	V	V _{GS} =0V, I _{SD} =8A
I _{AS}	Avalanche Current				А	V_{DD} =30V, V_{GS} =10V, R _G =25 Ω , L=0.5mH
T _J , T _{STG}	Operating and Storage Temperature	-55℃ to 150℃ Max.				

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